

Application/Control No.	Applicant(s)/Pate Reexamination	ent under
10/687,924	FLAUTNER ET	AL.
Examiner	Art Unit	
Harold Kim	2182	

	SEARCHED				
Class	Subclass	Date	Examiner		
713	320-322	6/25/2005	нк		
702	182, 183,	8/25/2005	НК		
710	15	8/25/2005	НК		
		- % -			
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INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner	
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
USPAT, USPGPUB, JPO, EPO, IEEE, NPL, see attached search note	6/25/2005	нк		
Inventor search on eDAN including 10/687972, 10/687928, 10/633360, 10/715368, 10/715410, 10/202057	6/25/2005	нк		

Aprold 6 d 25/2005